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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Not For New Designs
Core Processor	e200z0h
Core Size	32-Bit Single-Core
Speed	64MHz
Connectivity	CANbus, LINbus, SPI, UART/USART
Peripherals	DMA, POR, PWM, WDT
Number of I/O	107
Program Memory Size	512KB (512K x 8)
Program Memory Type	FLASH
EEPROM Size	64K x 8
RAM Size	40K x 8
Voltage - Supply (Vcc/Vdd)	4.5V ~ 5.5V
Data Converters	A/D 26x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	144-LQFP
Supplier Device Package	144-LQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/spc560p50l5beaar

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1.5.9 Frequency-modulated phase-locked loop (FMPLL)

The FMPLL allows the user to generate high speed system clocks from a 4–40 MHz input clock. Further, the FMPLL supports programmable frequency modulation of the system clock. The PLL multiplication factor, output clock divider ratio are all software configurable.

The PLL has the following major features:

- Input clock frequency: 4–40 MHz
- Maximum output frequency: 64 MHz
- Voltage controlled oscillator (VCO)—frequency 256–512 MHz
- Reduced frequency divider (RFD) for reduced frequency operation without forcing the PLL to relock
- Frequency-modulated PLL
 - Modulation enabled/disabled through software
 - Triangle wave modulation
- Programmable modulation depth ($\pm 0.25\%$ to $\pm 4\%$ deviation from center frequency): programmable modulation frequency dependent on reference frequency
- Self-clocked mode (SCM) operation

1.5.10 Main oscillator

The main oscillator provides these features:

- Input frequency range: 4–40 MHz
- Crystal input mode or oscillator input mode
- PLL reference

1.5.11 Internal RC oscillator

This device has an RC ladder phase-shift oscillator. The architecture uses constant current charging of a capacitor. The voltage at the capacitor is compared by the stable bandgap reference voltage.

The RC oscillator provides these features:

- Nominal frequency 16 MHz
- $\pm 5\%$ variation over voltage and temperature after process trim
- Clock output of the RC oscillator serves as system clock source in case loss of lock or loss of clock is detected by the PLL
- RC oscillator is used as the default system clock during startup

1.5.12 Periodic interrupt timer (PIT)

The PIT module implements these features:

- 4 general purpose interrupt timers
- 32-bit counter resolution
- Clocked by system clock frequency
- Each channel can be used as trigger for a DMA request

The sources of the ECC errors are:

- Flash memory
- SRAM

1.5.19 Peripheral bridge (PBRIDGE)

The PBRIDGE implements the following features:

- Duplicated periphery
- Master access privilege level per peripheral (per master: read access enable; write access enable)
- Write buffering for peripherals
- Checker applied on PBRIDGE output toward periphery
- Byte endianness swap capability

1.5.20 Controller area network (FlexCAN)

The SPC560P44Lx, SPC560P50Lx MCU contains one controller area network (FlexCAN) module. This module is a communication controller implementing the CAN protocol according to Bosch Specification version 2.0B. The CAN protocol was designed to be used primarily as a vehicle serial data bus, meeting the specific requirements of this field: real-time processing, reliable operation in the EMI environment of a vehicle, cost-effectiveness and required bandwidth. The FlexCAN module contains 32 message buffers.

Table 5. Supply pins (continued)

Supply		Pin	
Symbol	Description	100-pin	144-pin
V _{DD_LV_COR1}	1.2 V Decoupling pins for core logic. Decoupling capacitor must be connected between these pins and the nearest V _{SS_LV_COR} pin.	65	93
V _{SS_LV_COR1}	1.2 V Decoupling pins for core logic. Decoupling capacitor must be connected between these pins and the nearest V _{DD_LV_COR} pin.	66	94
V _{DD_LV_COR2}	1.2 V Decoupling pins for core logic. Decoupling capacitor must be connected between these pins and the nearest V _{SS_LV_COR} pin.	92	131
V _{SS_LV_COR2}	1.2 V Decoupling pins for core logic. Decoupling capacitor must be connected between these pins and the nearest V _{DD_LV_COR} pin.	93	132
V _{DD_LV_COR3}	1.2 V Decoupling pins for on-chip PLL modules. Decoupling capacitor must be connected between this pin and V _{SS_LV_COR3} .	25	36
V _{SS_LV_COR3}	1.2 V Decoupling pins for on-chip PLL modules. Decoupling capacitor must be connected between this pin and V _{DD_LV_COR3} .	24	35

1. Analog supply/ground and high/low reference lines are internally physically separate, but are shorted via a double-bonding connection on V_{DD_HV_ADCx}/V_{SS_HV_ADCx} pins.

2. Not available on 100-pin package.

2.2.2 System pins

[Table 5](#) and [Table 6](#) contain information on pin functions for the SPC560P44Lx, SPC560P50Lx devices. The pins listed in [Table 6](#) are single-function pins. The pins shown in [Table 7](#) are multi-function pins, programmable via their respective Pad Configuration Register (PCR) values.

Table 6. System pins

Symbol	Description	Direction	Pad speed ⁽¹⁾		Pin	
			SRC = 0	SRC = 1	100-pin	144-pin
Dedicated pins. Available on 100-pin and 144-pin package.						
MDO[0]	Nexus Message Data Output—line 0	Output only	Fast		—	9
NMI	Non-Maskable Interrupt	Input only	Slow	—	1	1
XTAL	Analog output of the oscillator amplifier circuit; needs to be grounded if oscillator is used in bypass mode	—	—	—	18	29
EXTAL	– Analog input of oscillator amplifier circuit, when oscillator not in bypass mode – Analog input for clock generator when oscillator in bypass mode	—	—	—	19	30

Table 7. Pin muxing (continued)

Port pin	Pad configuration register (PCR)	Alternate function ⁽¹⁾ , (2)	Functions	Peripheral ⁽³⁾	I/O direction ⁽⁴⁾	Pad speed ⁽⁵⁾		Pin No.	
						SRC = 0	SRC = 1	100-pin	144-pin
A[7]	PCR[7]	ALT0 ALT1 ALT2 ALT3 —	GPIO[7] SOUT — — EIRQ[7]	SIUL DSPI_1 — — SIUL	I/O O — — I	Slow	Medium	4	10
A[8]	PCR[8]	ALT0 ALT1 ALT2 ALT3 — —	GPIO[8] — — — SIN EIRQ[8]	SIUL — — — DSPI_1 SIUL	I/O — — — I I	Slow	Medium	6	12
A[9]	PCR[9]	ALT0 ALT1 ALT2 ALT3 —	GPIO[9] CS1 — B[3] FAULT[0]	SIUL DSPI_2 — FlexPWM_0 FlexPWM_0	I/O O — O I	Slow	Medium	94	134
A[10]	PCR[10]	ALT0 ALT1 ALT2 ALT3 —	GPIO[10] CS0 B[0] X[2] EIRQ[9]	SIUL DSPI_2 FlexPWM_0 FlexPWM_0 SIUL	I/O I/O O I/O I	Slow	Medium	81	118
A[11]	PCR[11]	ALT0 ALT1 ALT2 ALT3 —	GPIO[11] SCK A[0] A[2] EIRQ[10]	SIUL DSPI_2 FlexPWM_0 FlexPWM_0 SIUL	I/O I/O O O I	Slow	Medium	82	120
A[12]	PCR[12]	ALT0 ALT1 ALT2 ALT3 —	GPIO[12] SOUT A[2] B[2] EIRQ[11]	SIUL DSPI_2 FlexPWM_0 FlexPWM_0 SIUL	I/O O O O I	Slow	Medium	83	122
A[13]	PCR[13]	ALT0 ALT1 ALT2 ALT3 — — —	GPIO[13] — B[2] — SIN FAULT[0] EIRQ[12]	SIUL — FlexPWM_0 — DSPI_2 FlexPWM_0 SIUL	I/O — O — I I I	Slow	Medium	95	136

Table 11. Recommended operating conditions (3.3 V) (continued)

Symbol	Parameter	Conditions	Value		Unit
			Min	Max ⁽¹⁾	
$V_{SS_LV_CORx}^{(4)}$	SR	Internal reference voltage	—	0	V
T_A	SR	Ambient temperature under bias	$f_{CPU} = 64 \text{ MHz}$	−40	105
			$f_{CPU} = 60 \text{ MHz}$	−40	125

- Parametric figures can be out of specification when voltage drops below 4.5 V, however, guaranteeing the full functionality. In particular, ADC electrical characteristics and I/Os DC electrical specification may not be guaranteed.
- The difference between each couple of voltage supplies must be less than 100 mV, $|V_{DD_HV_IOy} - V_{DD_HV_IOx}| < 100 \text{ mV}$.
- The difference between each couple of voltage supplies must be less than 100 mV, $|V_{DD_HV_ADC1} - V_{DD_HV_ADC0}| < 100 \text{ mV}$. As long as that condition is met, ADC_0 and ADC_1 can be operated at 5 V with the rest of the device operating at 3.3 V.
- To be connected to emitter of external NPN. Low voltage supplies are not under user control—they are produced by an on-chip voltage regulator—but for the device to function properly the low voltage grounds ($V_{SS_LV_xxx}$) must be shorted to high voltage grounds ($V_{SS_HV_xxx}$) and the low voltage supply pins ($V_{DD_LV_xxx}$) must be connected to the external ballast emitter.
- The low voltage supplies ($V_{DD_LV_xxx}$) are not all independent.
 $V_{DD_LV_COR1}$ and $V_{DD_LV_COR2}$ are shorted internally via double bonding connections with lines that provide the low voltage supply to the data flash module. Similarly, $V_{SS_LV_COR1}$ and $V_{SS_LV_COR2}$ are internally shorted.
 $V_{DD_LV_REGCOR}$ and $V_{DD_LV_REGCORx}$ are physically shorted internally, as are $V_{SS_LV_REGCOR}$ and $V_{SS_LV_CORx}$.

Figure 7 shows the constraints of the different power supplies.

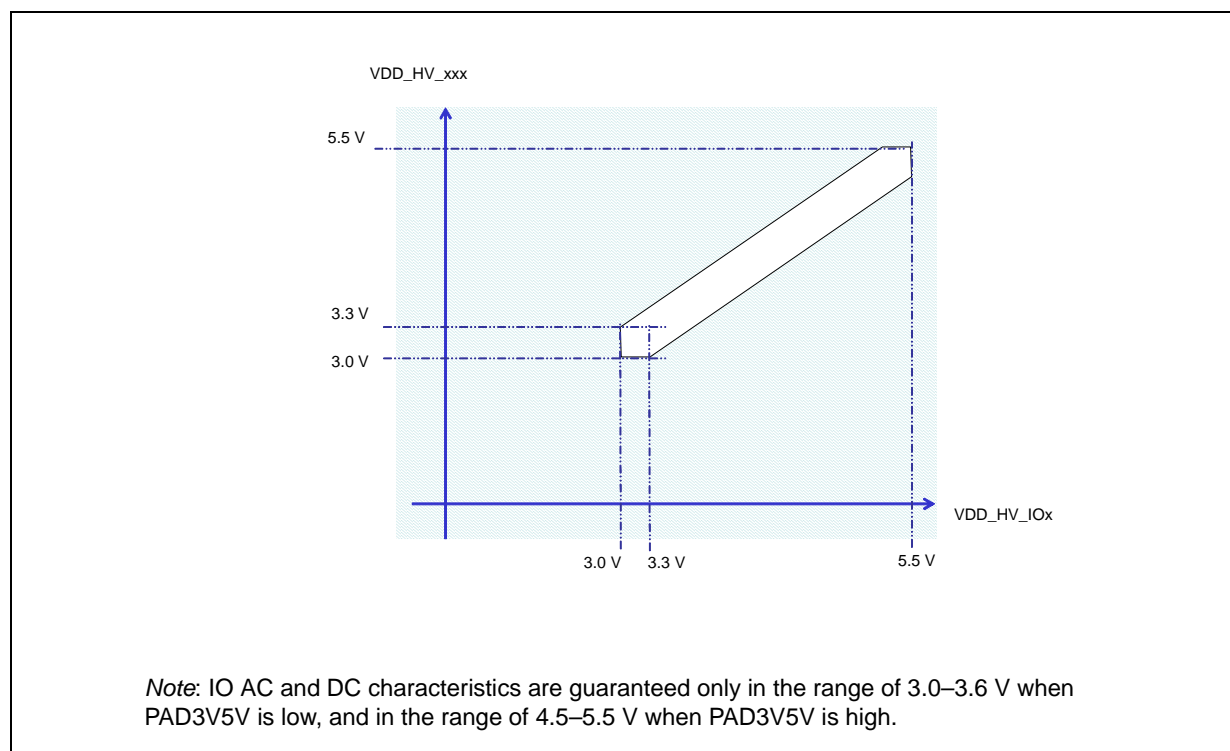
Figure 7. Power supplies constraints ($3.0 \text{ V} \leq V_{DD_HV_IOx} \leq 5.5 \text{ V}$)

Table 16. Approved NPN ballast components (configuration with resistor on base)

Part	Manufacturer	Approved derivatives ⁽¹⁾
BC817	Infineon	BC817-16;BC817-25;BC817SU;
	NXP	BC817-16;BC817-25
BCP56	ST	BCP56-16
	Infineon	BCP56-10;BCP56-16
	ON Semi	BCP56-10
	NXP	BCP56-10;BCP56-16

1. For automotive applications please check with the appropriate transistor vendor for automotive grade certification

Table 17. Voltage regulator electrical characteristics (configuration with resistor on base)

Symbol		C	Parameter	Conditions	Value			Unit
					Min	Typ	Max	
$V_{DD_LV_REGCOR}$	CC	P	Output voltage under maximum load run supply current configuration	Post-trimming	1.15	—	1.32	V
R_B	SR	—	External resistance on bipolar junction transistor (BJT) base	—	18	—	22	k Ω
C_{DEC1}	SR	—	External decoupling/stability ceramic capacitor	BJT from Table 16 , 3 capacitances (i.e. X7R or X8R capacitors) with nominal value of 10 μ F	19.5	30	—	μ F
				BJT BC817, one capacitance of 22 μ F	14.3	22	—	μ F
R_{REG}	SR	—	Resulting ESR of all three capacitors of C_{DEC1}	BJT from Table 16 , 3x10 μ F. Absolute maximum value between 100 kHz and 10 MHz	—	—	50	m Ω
			Resulting ESR of the unique capacitor C_{DEC1}	BJT BC817, 1x 22 μ F. Absolute maximum value between 100 kHz and 10 MHz	10	—	40	m Ω
C_{DEC2}	SR	—	External decoupling/stability ceramic capacitor	4 capacitances (i.e. X7R or X8R capacitors) with nominal value of 440 nF	1200	1760	—	nF
C_{DEC3}	SR	—	External decoupling/stability ceramic capacitor on $V_{DD_HV_REG}$	3 capacitances (i.e. X7R or X8R capacitors) with nominal value of 10 μ F; C_{DEC3} has to be equal or greater than C_{DEC1}	19.5	30	—	μ F
L_{Reg}	SR	—	Resulting ESL of $V_{DD_HV_REG}$, BCTRL and $V_{DD_LV_CORx}$ pins	—	—	—	15	nH

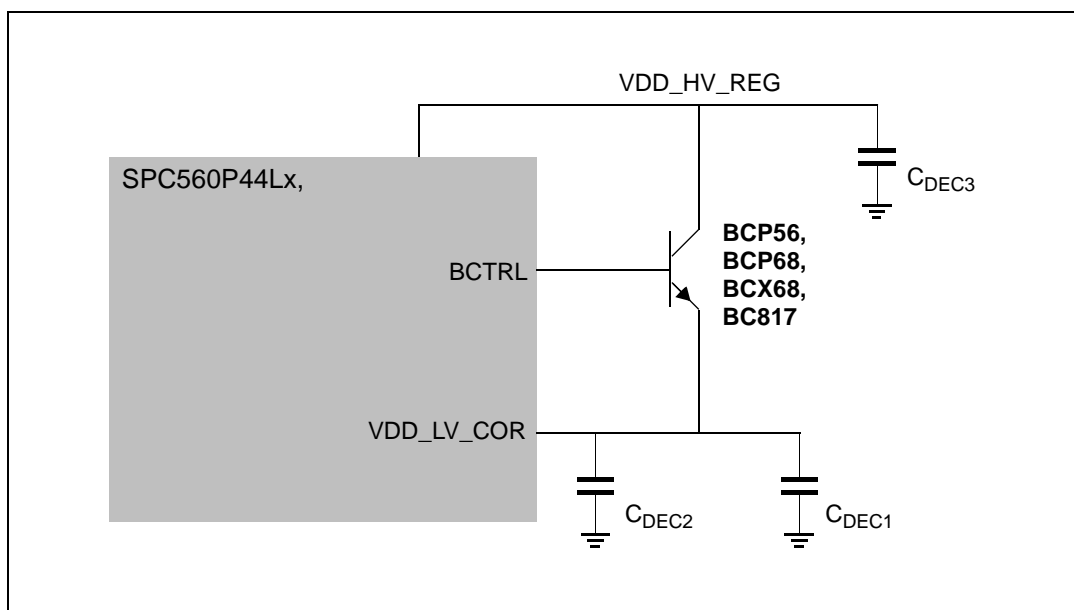


Figure 10. Configuration without resistor on base

Table 18. Voltage regulator electrical characteristics (configuration without resistor on base)

Symbol	C	Parameter	Conditions	Value			Unit
				Min	Typ	Max	
$V_{DD_LV_REGCOR}$	CC	P	Output voltage under maximum load run supply current configuration	1.15	—	1.32	V
C_{DEC1}	SR	—	External decoupling/stability ceramic capacitor	40	56	—	μF
R_{REG}	SR	—	Resulting ESR of all four C_{DEC1}	—	—	45	m Ω
C_{DEC2}	SR	—	External decoupling/stability ceramic capacitor	400	—	—	nF
C_{DEC3}	SR	—	External decoupling/stability ceramic capacitor on $V_{DD_HV_REG}$	40	—	—	μF
L_{Reg}	SR	—	Resulting ESL of $V_{DD_HV_REG}$, BCTRL and $V_{DD_LV_CORx}$ pins	—	—	15	nH

3.8.2 Voltage monitor electrical characteristics

The device implements a Power-on Reset module to ensure correct power-up initialization, as well as three low voltage detectors to monitor the V_{DD} and the V_{DD_LV} voltage while device is supplied:

- POR monitors V_{DD} during the power-up phase to ensure device is maintained in a safe reset state
- LVDHV3 monitors V_{DD} to ensure device reset below minimum functional supply
- LVDHV5 monitors V_{DD} when application uses device in the $5.0\text{ V} \pm 10\%$ range
- LVDLVCOR monitors low voltage digital power domain

Table 19. Low voltage monitor electrical characteristics

Symbol	C	Parameter	Conditions (1)	Value		Unit
				Min	Max	
V_{PORH}	T	Power-on reset threshold	—	1.5	2.7	V
V_{PORUP}	P	Supply for functional POR module	$T_A = 25\text{ °C}$	1.0	—	V
$V_{REGLVDMOK_H}$	P	Regulator low voltage detector high threshold	—	—	2.95	V
$V_{REGLVDMOK_L}$	P	Regulator low voltage detector low threshold	—	2.6	—	V
$V_{FLLVDMOK_H}$	P	Flash low voltage detector high threshold	—	—	2.95	V
$V_{FLLVDMOK_L}$	P	Flash low voltage detector low threshold	—	2.6	—	V
$V_{IOLVDMOK_H}$	P	I/O low voltage detector high threshold	—	—	2.95	V
$V_{IOLVDMOK_L}$	P	I/O low voltage detector low threshold	—	2.6	—	V
$V_{IOLVDM5OK_H}$	P	I/O 5V low voltage detector high threshold	—	—	4.4	V
$V_{IOLVDM5OK_L}$	P	I/O 5V low voltage detector low threshold	—	3.8	—	V
$V_{MLVDDOK_H}$	P	Digital supply low voltage detector high	—	—	1.145	V
$V_{MLVDDOK_L}$	P	Digital supply low voltage detector low	—	1.08	—	V

1. $V_{DD} = 3.3\text{V} \pm 10\% / 5.0\text{V} \pm 10\%$, $T_A = -40\text{ °C}$ to T_{A_MAX} , unless otherwise specified

3.9 Power up/down sequencing

To prevent an overstress event or a malfunction within and outside the device, the SPC560P44Lx, SPC560P50Lx implements the following sequence to ensure each module is started only when all conditions for switching it ON are available:

- A POWER_ON module working on voltage regulator supply controls the correct start-up of the regulator. This is a key module ensuring safe configuration for all voltage regulator functionality when supply is below 1.5V. Associated POWER_ON (or POR) signal is active low.
- Several low voltage detectors, working on voltage regulator supply monitor the voltage of the critical modules (voltage regulator, I/Os, flash memory and low voltage domain). LVDs are gated low when POWER_ON is active.
- A POWER_OK signal is generated when all critical supplies monitored by the LVD are available. This signal is active high and released to all modules including I/Os, flash

Table 24. Supply current (3.3 V, NVUSRO[PAD3V5V] = 1)

Symbol	C	Parameter	Conditions	Value		Unit
				Typ	Max	
I _{DD_LV_CORx}	T	RUN—Maximum mode ⁽¹⁾	V _{DD_LV_CORx} externally forced at 1.3 V	40 MHz	62	77
				64 MHz	71	89
		RUN—Typical mode ⁽²⁾		40 MHz	45	56
				64 MHz	53	66
	P	RUN—Maximum mode ⁽³⁾	V _{DD_LV_CORx} externally forced at 1.3 V	64 MHz	60	75
		HALT mode ⁽⁴⁾	V _{DD_LV_CORx} externally forced at 1.3 V	—	1.5	10
STOP mode ⁽⁵⁾		V _{DD_LV_CORx} externally forced at 1.3 V	—	1	10	
I _{DD_FLASH}	T	Flash during read on single mode	V _{DD_HV_FL} at 3.3 V	—	8	10
		Flash during erase operation on single mode	V _{DD_HV_FL} at 3.3 V	—	10	12
I _{DD_ADC}	T	ADC—Maximum mode ⁽¹⁾	V _{DD_HV_ADC0} at 3.3 V V _{DD_HV_ADC1} at 3.3 V f _{ADC} = 16 MHz	ADC_1	2.5	4
				ADC_0	2	4
		ADC—Typical mode ⁽²⁾		ADC_1	0.8	1
				ADC_0	0.005	0.006
I _{DD_OSC}	T	Oscillator	V _{DD_OSC} at 3.3 V	8 MHz	2.4	3

1. Maximum mode: FlexPWM, ADCs, CTU, DSPI, LINFlex, FlexCAN, 15 output pins, 1st and 2nd PLL enabled. I/O supply current excluded.
2. Typical mode: DSPI, LINFlex, FlexCAN, 15 output pins, 1st PLL only. I/O supply current excluded.
3. Code fetched from RAM, PLL_0: 64 MHz system clock (x4 multiplier with 16 MHz XTAL), PLL_1 is ON at PHI_div2 = 120 MHz and PHI_div3 = 80 MHz, auxiliary clock sources set that all peripherals receive maximum frequency, all peripherals enabled.
4. Halt mode configurations: code fetched from RAM, code and data flash memories in low power mode, OSC/PLL_0/PLL_1 are OFF, core clock frozen, all peripherals are disabled.
5. STOP "P" mode Device Under Test (DUT) configuration: code fetched from RAM, code and data flash memories OFF, OSC/PLL_0/PLL_1 are OFF, core clock frozen, all peripherals are disabled.

3.10.4 Input DC electrical characteristics definition

Figure 14 shows the DC electrical characteristics behavior as function of time.

Table 26. I/O weight (continued)

Pad	LQFP144		LQFP100	
	Weight 5V	Weight 3.3V	Weight 5V	Weight 3.3V
PAD[27]	1%	1%	1%	1%
PAD[28]	1%	1%	1%	1%
PAD[63]	1%	1%	1%	1%
PAD[72]	1%	1%	—	—
PAD[29]	1%	1%	1%	1%
PAD[73]	1%	1%	—	—
PAD[31]	1%	1%	1%	1%
PAD[74]	1%	1%	—	—
PAD[30]	1%	1%	1%	1%
PAD[75]	1%	1%	—	—
PAD[32]	1%	1%	1%	1%
PAD[76]	1%	1%	—	—
PAD[64]	1%	1%	1%	1%
PAD[0]	23%	20%	23%	20%
PAD[1]	21%	18%	21%	18%
PAD[107]	20%	17%	—	—
PAD[58]	19%	16%	19%	16%
PAD[106]	18%	16%	—	—
PAD[59]	17%	15%	17%	15%
PAD[105]	16%	14%	—	—
PAD[43]	15%	13%	15%	13%
PAD[104]	14%	13%	—	—
PAD[44]	13%	12%	13%	12%
PAD[103]	12%	11%	—	—
PAD[2]	11%	10%	11%	10%
PAD[101]	11%	9%	—	—
PAD[21]	10%	8%	10%	8%
TMS	1%	1%	1%	1%
TCK	1%	1%	1%	1%
PAD[20]	16%	11%	16%	11%
PAD[3]	4%	3%	4%	3%
PAD[61]	9%	8%	9%	8%
PAD[102]	11%	10%	—	—

Table 27. I/O consumption (continued)

Symbol		C	Parameter	Conditions ⁽¹⁾		Value			Unit
						Min	Typ	Max	
I _{RMSMED}	CC	D	Root medium square I/O current for MEDIUM configuration	C _L = 25 pF, 13 MHz	V _{DD} = 5.0 V ± 10%, PAD3V5V = 0	—	—	6.6	mA
				C _L = 25 pF, 40 MHz		—	—	13.4	
				C _L = 100 pF, 13 MHz		—	—	18.3	
				C _L = 25 pF, 13 MHz	V _{DD} = 3.3 V ± 10%, PAD3V5V = 1	—	—	5	
				C _L = 25 pF, 40 MHz		—	—	8.5	
				C _L = 100 pF, 13 MHz		—	—	11	
I _{RMSFST}	CC	D	Root medium square I/O current for FAST configuration	C _L = 25 pF, 40 MHz	V _{DD} = 5.0 V ± 10%, PAD3V5V = 0	—	—	22	mA
				C _L = 25 pF, 64 MHz		—	—	33	
				C _L = 100 pF, 40 MHz		—	—	56	
				C _L = 25 pF, 40 MHz	V _{DD} = 3.3 V ± 10%, PAD3V5V = 1	—	—	14	
				C _L = 25 pF, 64 MHz		—	—	20	
				C _L = 100 pF, 40 MHz		—	—	35	
I _{AVGSEG}	SR	D	Sum of all the static I/O current within a supply segment	V _{DD} = 5.0 V ± 10%, PAD3V5V = 0		—	—	70	mA
				V _{DD} = 3.3 V ± 10%, PAD3V5V = 1		—	—	65	

1. $V_{DD} = 3.3 \text{ V} \pm 10\%$ / $5.0 \text{ V} \pm 10\%$, $T_A = -40$ to $125 \text{ }^\circ\text{C}$, unless otherwise specified

2. Stated maximum values represent peak consumption that lasts only a few ns during I/O transition.

3.11 Main oscillator electrical characteristics

The SPC560P44Lx, SPC560P50Lx provides an oscillator/resonator driver.

Table 28. Main oscillator output electrical characteristics (5.0 V, NVUSRO[PAD3V5V] = 0)

Symbol		C	Parameter	Value		Unit
				Min	Max	
f_{OSC}	SR	—	Oscillator frequency	4	40	MHz
g_m	—	P	Transconductance	6.5	25	mA/V
V_{OSC}	—	T	Oscillation amplitude on XTAL pin	1	—	V
t_{OSCSU}	—	T	Start-up time ^{(1),(2)}	8	—	ms

1. The start-up time is dependent upon crystal characteristics, board leakage, etc., high ESR and excessive capacitive loads can cause long start-up time.

2. Value captured when amplitude reaches 90% of XTAL

Table 31. FMPLL electrical characteristics (continued)

Symbol	C	Parameter		Conditions ⁽¹⁾	Value		Unit
					Min	Max	
C _{JITTER}	T	CLKOUT period jitter ^{(6),(7),(8),(9)}	Short-term jitter ⁽¹⁰⁾	f _{SYS} maximum	−4	4	% f _{CLKOUT}
			Long-term jitter (avg. over 2 ms interval)	f _{PLLIN} = 16 MHz (resonator), f _{PLLCLK} at 64 MHz, 4000 cycles	—	10	ns
t _{ipll}	D	PLL lock time ^{(11), (12)}		—	—	200	μs
t _{dc}	D	Duty cycle of reference		—	40	60	%
f _{LCK}	D	Frequency LOCK range		—	−6	6	% f _{SYS}
f _{UL}	D	Frequency un-LOCK range		—	−18	18	% f _{SYS}
f _{CS} f _{DS}	D	Modulation depth		Center spread	±0.25	±4.0 ⁽¹³⁾	% f _{SYS}
				Down spread	−0.5	−8.0	
f _{MOD}	D	Modulation frequency ⁽¹⁴⁾		—	—	70	kHz

1. V_{DD_LV_CORx} = 1.2 V ±10%; V_{SS} = 0 V; T_A = −40 to 125 °C, unless otherwise specified
2. Considering operation with PLL not bypassed
3. “Loss of Reference Frequency” window is the reference frequency range outside of which the PLL is in self-clocked mode.
4. Self-clocked mode frequency is the frequency that the PLL operates at when the reference frequency falls outside the f_{LOR} window.
5. f_{VCO} self clock range is 20–150 MHz. f_{SCM} represents f_{SYS} after PLL output divider (ERFD) of 2 through 16 in enhanced mode.
6. This value is determined by the crystal manufacturer and board design.
7. Jitter is the average deviation from the programmed frequency measured over the specified interval at maximum f_{SYS}. Measurements are made with the device powered by filtered supplies and clocked by a stable external clock signal. Noise injected into the PLL circuitry via V_{DDPLL} and V_{SSPLL} and variation in crystal oscillator frequency increase the C_{JITTER} percentage for a given interval.
8. Proper PC board layout procedures must be followed to achieve specifications.
9. Values are with frequency modulation disabled. If frequency modulation is enabled, jitter is the sum of C_{JITTER} and either f_{CS} or f_{DS} (depending on whether center spread or down spread modulation is enabled).
10. Short term jitter is measured on the clock rising edge at cycle n and cycle n+4.
11. This value is determined by the crystal manufacturer and board design. For 4 MHz to 20 MHz crystals specified for this PLL, load capacitors should not exceed these limits.
12. This specification applies to the period required for the PLL to relock after changing the MFD frequency control bits in the synthesizer control register (SYNCR).
13. This value is true when operating at frequencies above 60 MHz, otherwise f_{CS} is 2% (above 64 MHz).
14. Modulation depth will be attenuated from depth setting when operating at modulation frequencies above 50 kHz.

Table 36. Flash memory read access timing

Symbol	C	Parameter	Conditions ⁽¹⁾	Max value	Unit
f_{\max}	C	Maximum working frequency at given number of wait states in worst conditions	2 wait states	66	MHz
			0 wait states	18	

1. $V_{DD} = 3.3 \text{ V} \pm 10\% / 5.0 \text{ V} \pm 10\%$, $T_A = -40$ to 125°C , unless otherwise specified

3.16 AC specifications

3.16.1 Pad AC specifications

Table 37. Output pin transition times

Symbol	C	Parameter	Conditions ⁽¹⁾	Value			Unit
				Min	Typ	Max	
t_{tr}	CC	Output transition time output pin ⁽²⁾ SLOW configuration	$C_L = 25 \text{ pF}$	—	—	50	ns
			$C_L = 50 \text{ pF}$	—	—	100	
			$C_L = 100 \text{ pF}$	—	—	125	
			$C_L = 25 \text{ pF}$	—	—	40	
			$C_L = 50 \text{ pF}$	—	—	50	
			$C_L = 100 \text{ pF}$	—	—	75	
t_{tr}	CC	Output transition time output pin ⁽²⁾ MEDIUM configuration	$C_L = 25 \text{ pF}$	—	—	10	ns
			$C_L = 50 \text{ pF}$	—	—	20	
			$C_L = 100 \text{ pF}$	—	—	40	
			$C_L = 25 \text{ pF}$	—	—	12	
			$C_L = 50 \text{ pF}$	—	—	25	
			$C_L = 100 \text{ pF}$	—	—	40	
t_{tr}	CC	Output transition time output pin ⁽²⁾ FAST configuration	$C_L = 25 \text{ pF}$	—	—	4	ns
			$C_L = 50 \text{ pF}$	—	—	6	
			$C_L = 100 \text{ pF}$	—	—	12	
			$C_L = 25 \text{ pF}$	—	—	4	
			$C_L = 50 \text{ pF}$	—	—	7	
			$C_L = 100 \text{ pF}$	—	—	12	
$t_{SYM}^{(3)}$	CC	Symmetric transition time, same drive strength between N and P transistor	$V_{DD} = 5.0 \text{ V} \pm 10\%$, $PAD3V5V = 0$	—	—	4	ns
			$V_{DD} = 3.3 \text{ V} \pm 10\%$, $PAD3V5V = 1$	—	—	5	

1. $V_{DD} = 3.3 \text{ V} \pm 10\% / 5.0 \text{ V} \pm 10\%$, $T_A = -40^\circ\text{C}$ to $T_{A \text{ MAX}}$, unless otherwise specified

2. C_L includes device and package capacitances ($C_{PKG} < 5 \text{ pF}$).

3. Transition timing of both positive and negative slopes will differ maximum 50%

Table 40. Nexus debug port timing⁽¹⁾ (continued)

No.	Symbol		C	Parameter	Value			Unit
					Min	Typ	Max	
6	t _{NTDIS}	CC	D	TDI data setup time	6	—	—	ns
	t _{NTMSS}	CC	D	TMS data setup time	6	—	—	ns
7	t _{NTDIH}	CC	D	TDI data hold time	10	—	—	ns
	t _{NTMSH}	CC	D	TMS data hold time	10	—	—	ns
8	t _{TDOV}	CC	D	TCK low to TDO data valid	—	—	35	ns
9	t _{TDOI}	CC	D	TCK low to TDO data invalid	6	—	—	ns

1. All Nexus timing relative to MCKO is measured from 50% of MCKO and 50% of the respective signal.
2. MDO, $\overline{\text{MSEO}}$, and $\overline{\text{EVTO}}$ data is held valid until next MCKO low cycle.
3. Lower frequency is required to be fully compliant to standard.

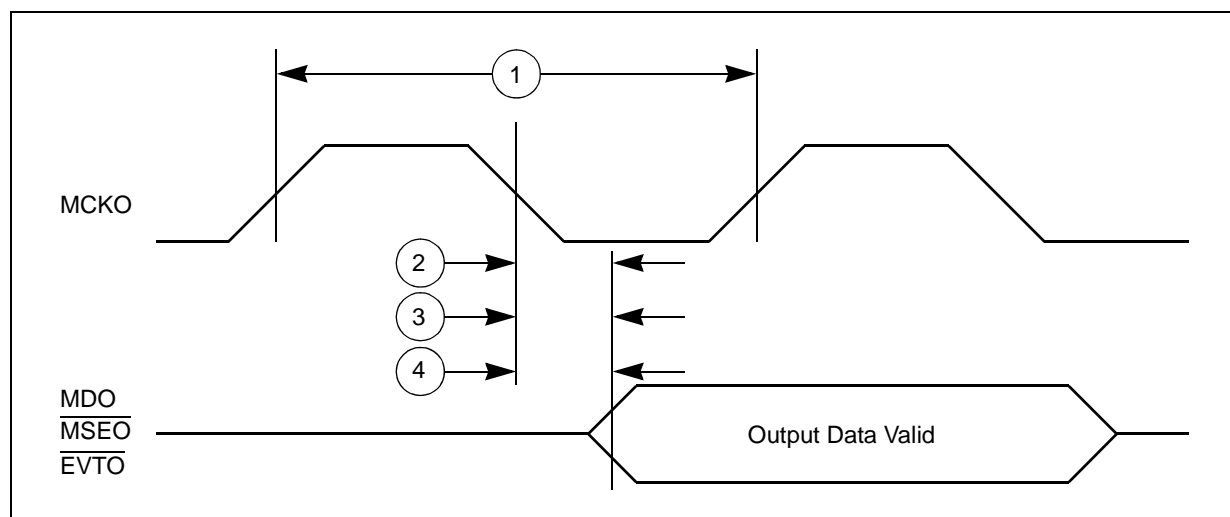


Figure 25. Nexus output timing

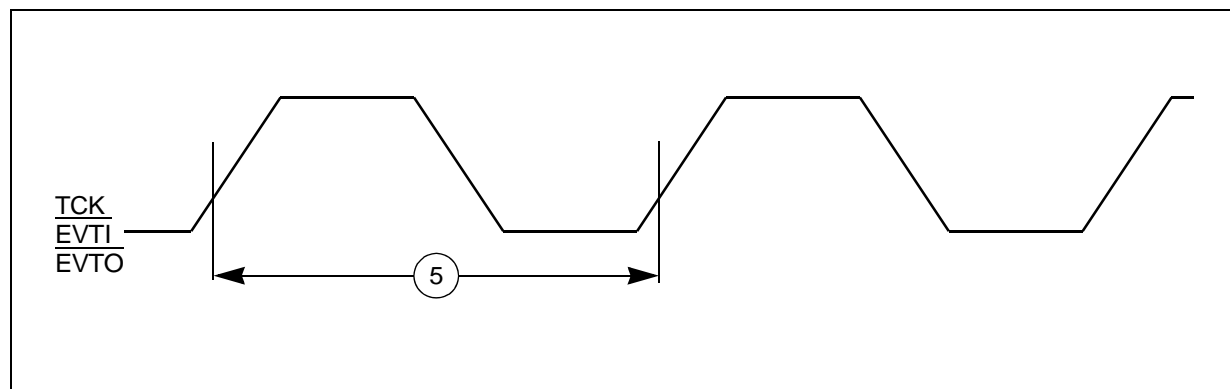


Figure 26. Nexus event trigger and test clock timings

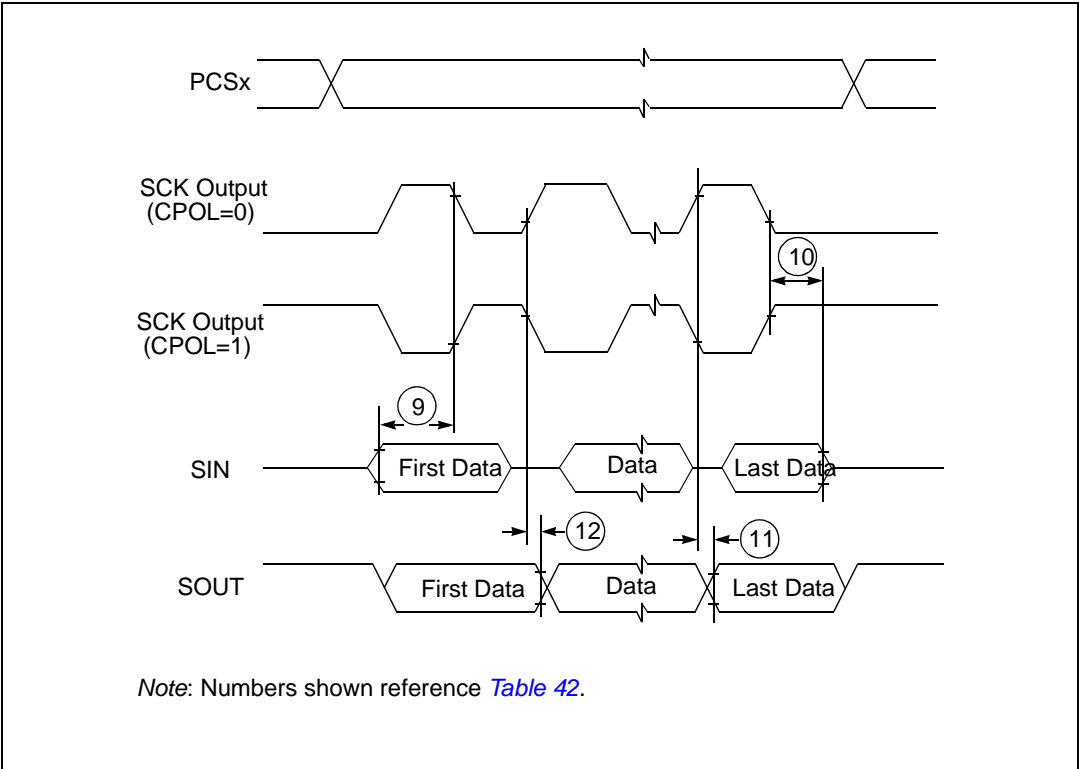


Figure 30. DSPI classic SPI timing – Master, CPHA = 1

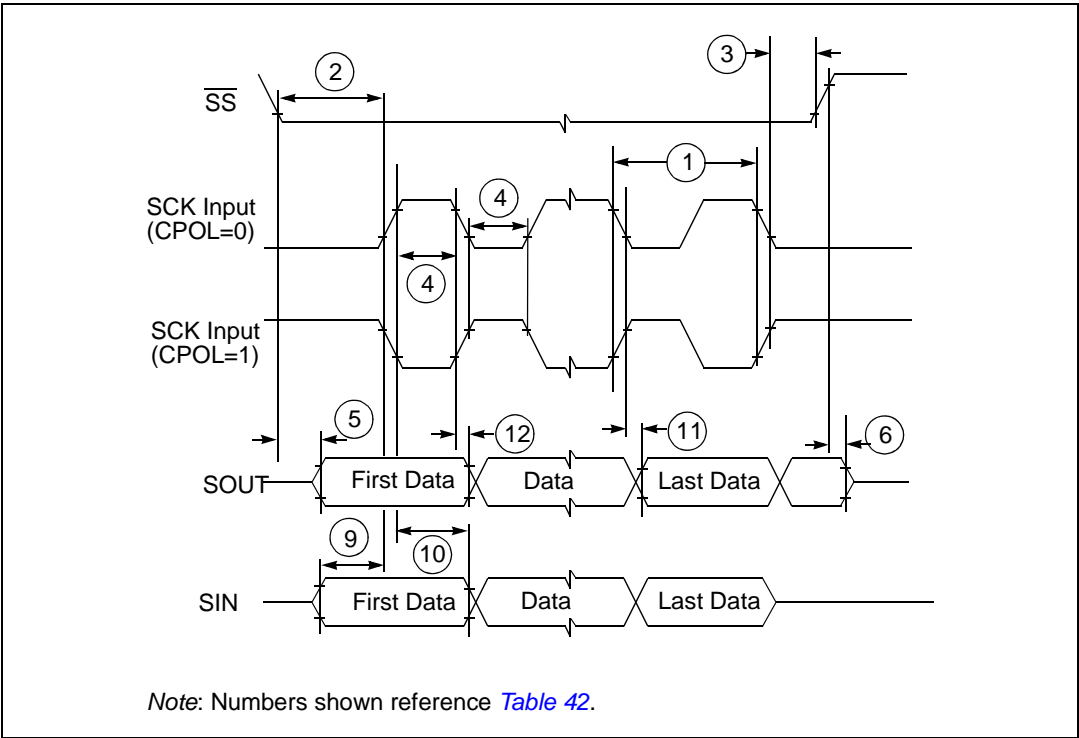


Figure 31. DSPI classic SPI timing – Slave, CPHA = 0

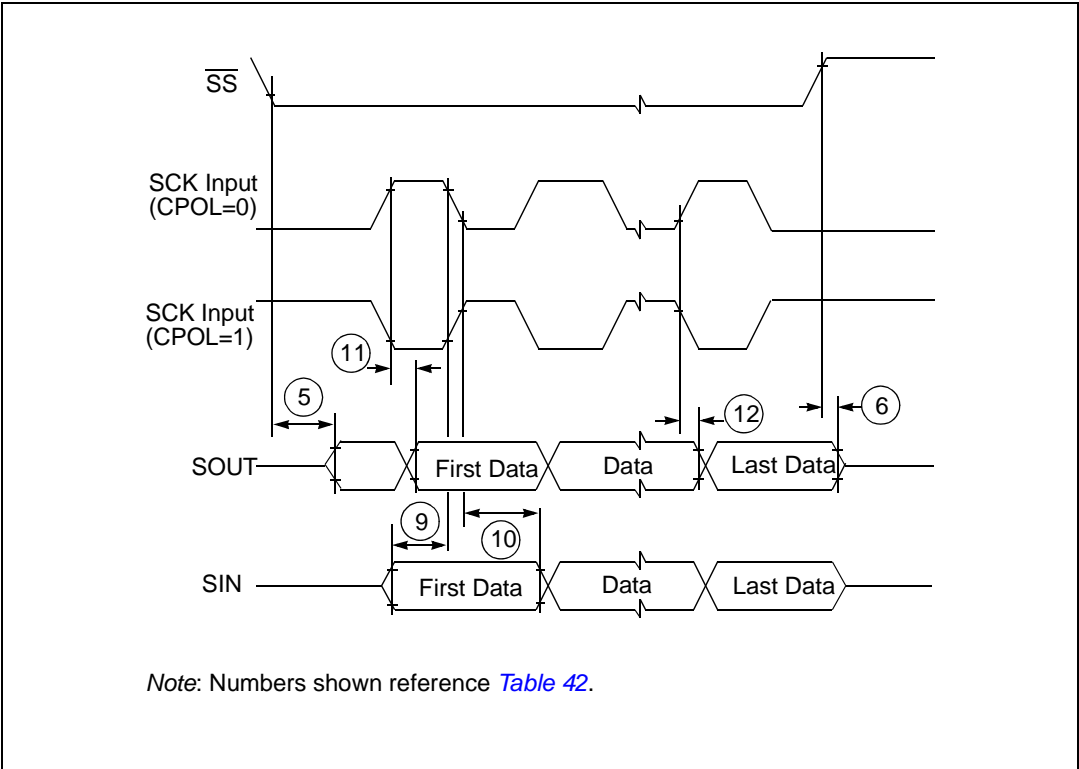


Figure 32. DSPI classic SPI timing – Slave, CPHA = 1

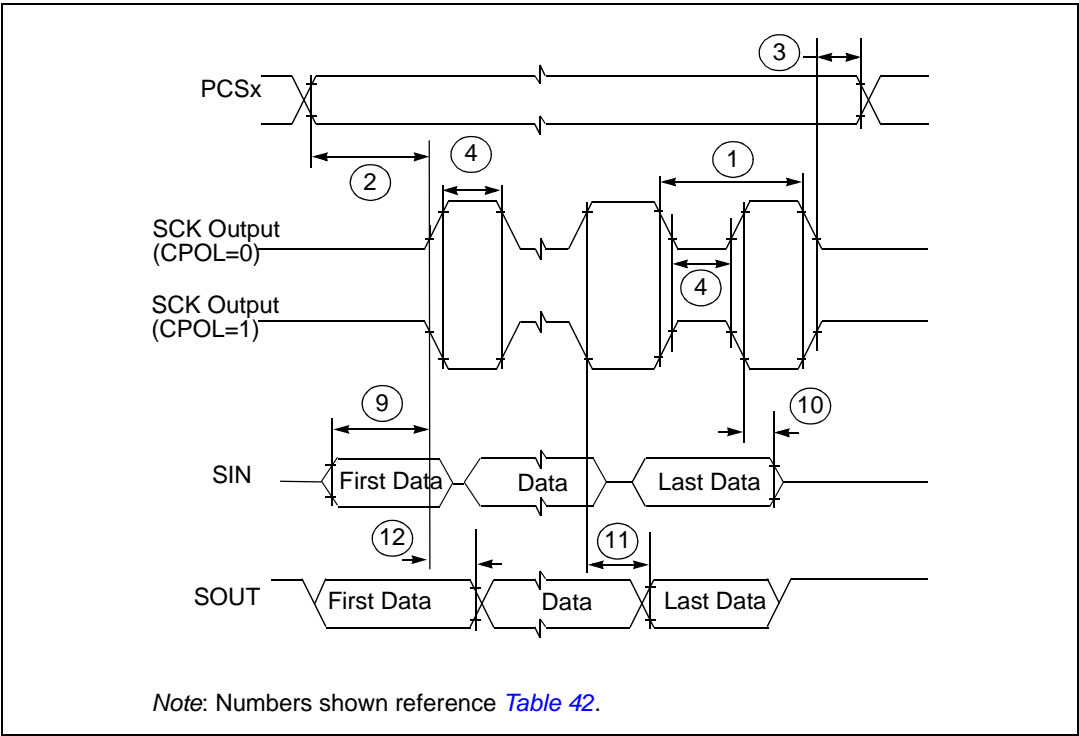


Figure 33. DSPI modified transfer format timing – Master, CPHA = 0

4 Package characteristics

4.1 ECOPACK®

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK® is an ST trademark.

4.2 Package mechanical data

4.2.1 LQFP144 mechanical outline drawing

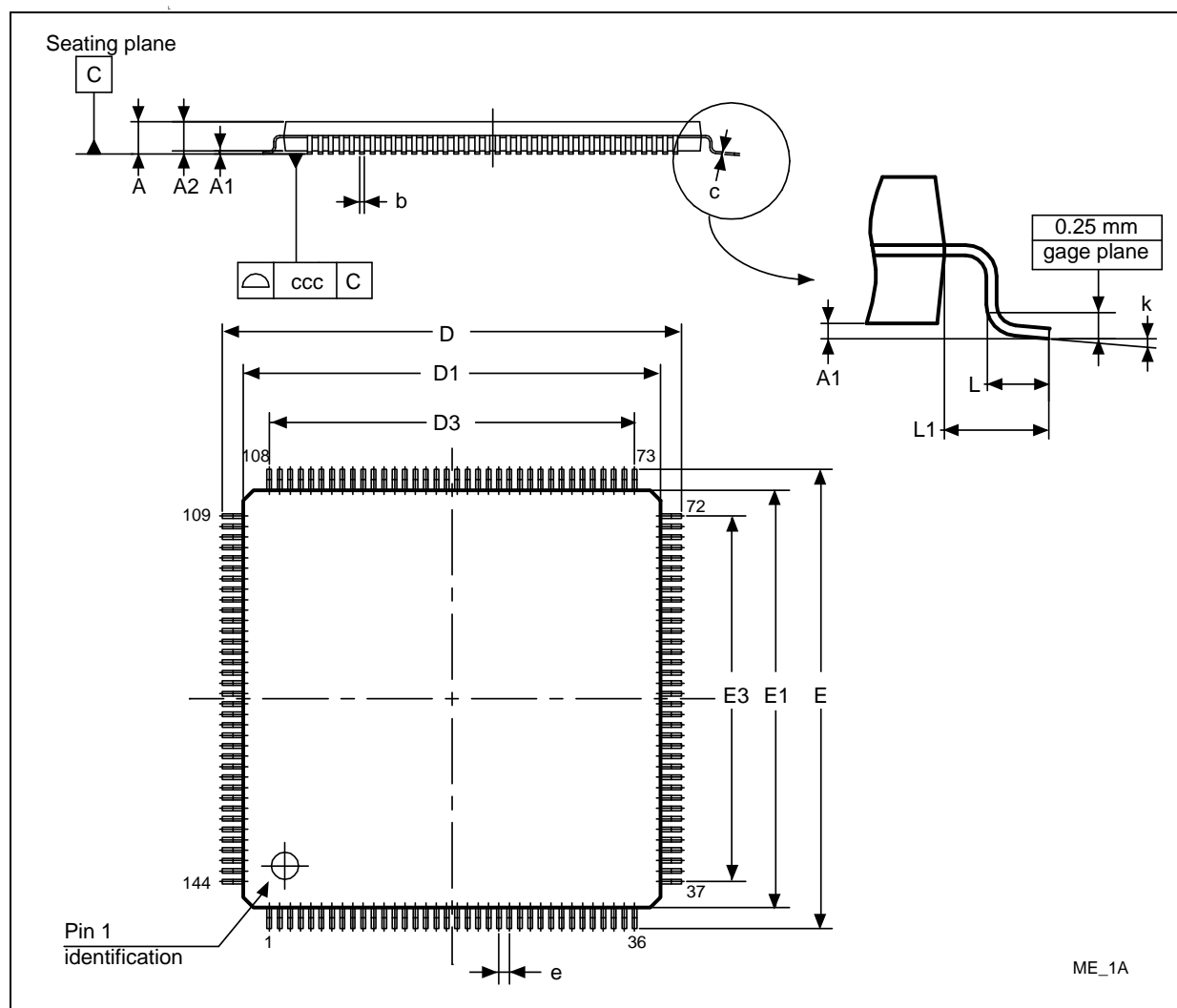


Figure 38. LQFP144 package mechanical drawing

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